PTO/SB/08A	OIPE	ATTY. DOCKET NO. JEV/KAR:1016.2019	SERIAL NO. (Cont. of 10/274,068)
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT		APPLICANT Randy J. Schwindt et al.	
(Use several sheets if necessal	12. AT/	FILING DATE Herewith	GROUP

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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FOREIGN PATENT DOCUMENTS

						TRANSLATION	
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	YES	NO
 AY	201205	12/1986	Europe				ļ
AZ	1-209380	8/23/1989	Japan				
ВА	2-220453	9/1990	Japan				

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OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

ВВ	Micromanipulator Company, Inc., "Test Station Accessories." (1983)		
ВС	Micromanipulator Company, Inc., "Model 8000 Test Station." (1986)		
BD	"Model TPO3000 Series Thermochuck® Systems," four-page product note, Temptronic Corporation, Newton, MA (May 1992 or earlier)		
BE			
BF	"Application Note 1 Controlled Environment Enclosure," two-page application note, Temptronic Corporation, Newton, MA (May 1992 or earlier)		
BG	Micromanipulator Company, Inc. "Model 8000 Test Station." (1988)		
вн	Applebay, Harry F. Deposition transcript (pp. 61-67) with exhibits 581 A.B.C. describing Flexion AP-1 probe station sold in 1987 (May 1988)		
BI	"Cross Section Signatone S-1240," one-page sketch prepared by Signatone counsel.		
ВЈ	"S-1240," two-page product note, Signatone, San Jose, CA (February 1988 or earlier per Signatone counsel)		
ВК	Y. Yamamoto, "A Compact Self-Shielding Prober" IEEE Trans., Inst. and Meas., Vol. 38, pp. 1088-1093 (1989)		
BL	Temptronic's "Guarded" Chuck, one-page note describing guarding system of Temptronic Corporation of Newton, MA, dated 11/15/89.		
ВМ	Beck & Tomann, "Chip Tester," IBM Technical Disclosure Bulletin, p. 4819 (January 1985).		
BN	Article by William Knauer entitled "Fixturing for Low-Current/Low Voltage Parametric Testing," appearing in Evaluation Engineering, (1990), pp. 150-153		
во	Hewlett-Packard, "Application Note 356-HP 4142B Modular DC Source/Monitor Practical Application," (Nov. 1987), pp. 1-4		
ВР	Hewlett-Packard, H-P Model 4284A Precision LCR Meter, Operation Manual (December 1991) pp. 1-2, 6-9 and 6-15		
XAMINER	DATE CONSIDERED		

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Information Disclosure Statement -PTO/SB/08A Added page 2 of 2